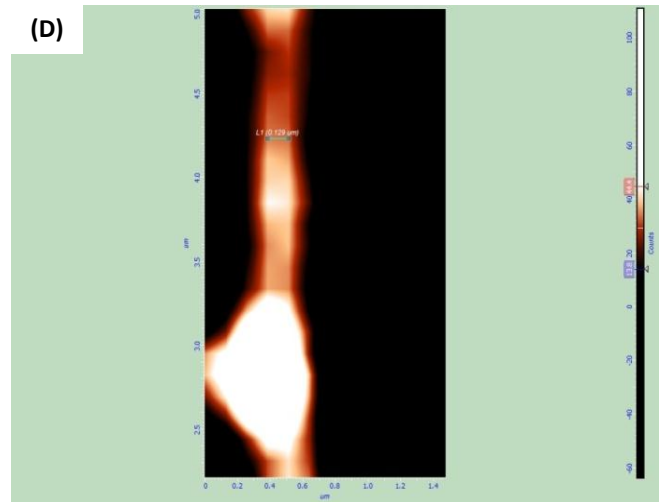
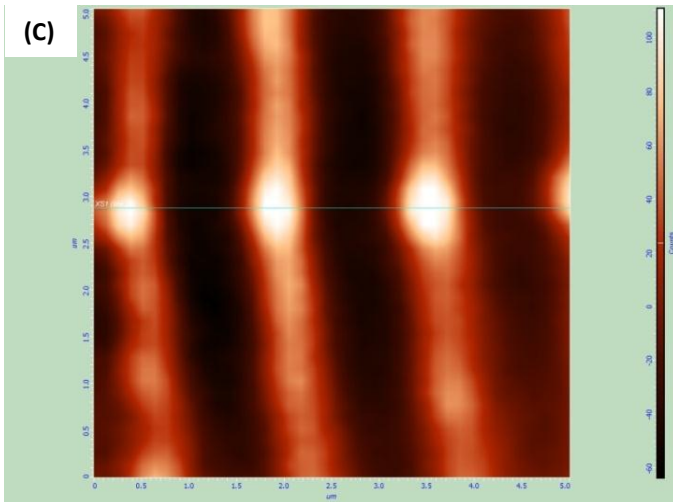
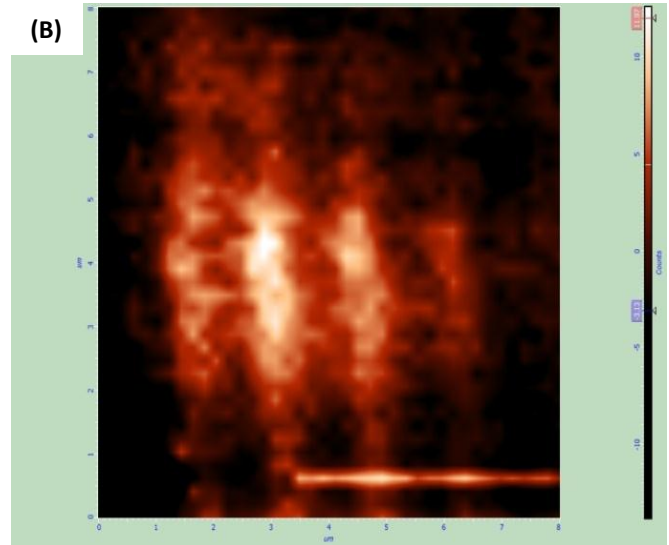
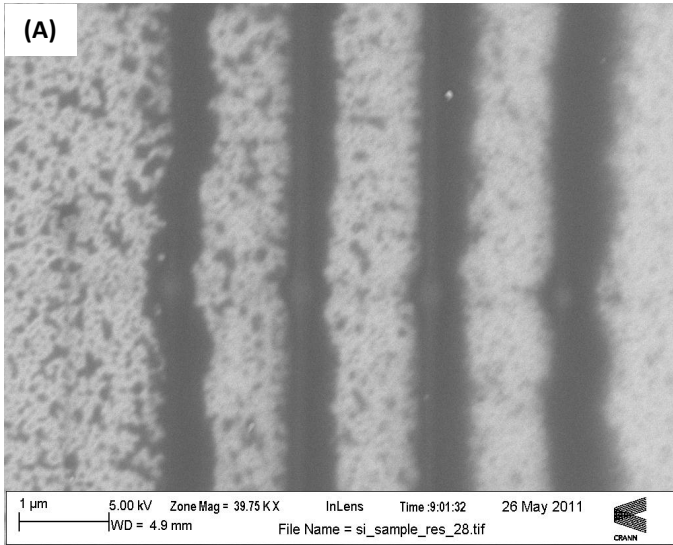


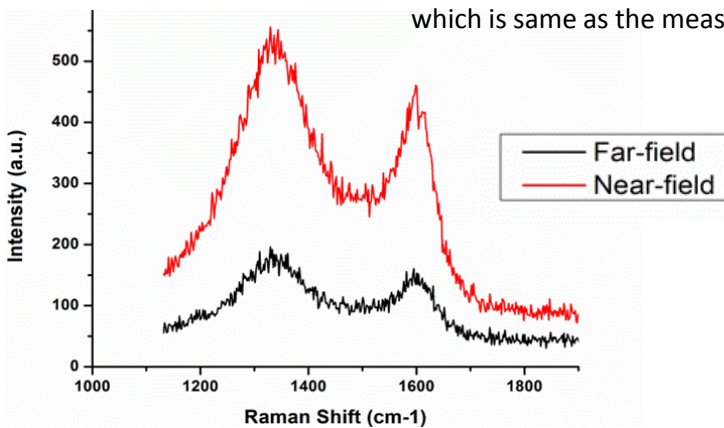


High Resolution Optical Microscopy

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(A) SEM image of carbon grid; (B) Far-field Raman image; (C) Near-field Raman image from same area by using our technology; (D) Zoom-in image from near-field Raman mapping. The width of the carbon wire is 129nm which is same as the measurement in SEM image.



Black line: Raman spectrum obtained from carbon grid by using normal Raman spectrometer.

Red line: Enhanced Raman spectrum of carbon grid from the same point by using our technology.

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